

SIDC56D120F6

Fast switching diode chip in Emitter Controlled Technology

Features:

- 1200V technology 120 µm chip
- soft, fast switching
- low reverse recovery charge
- small temperature coefficient
- qualified according to JEDEC for target applications

Recommended for:

power modules and discrete devices



Applications:

 SMPS, resonant applications, drives

Chip Type	V _R	I Fn	Die Size	Package
SIDC56D120F6	1200V	75A	7.5 x 7.5 mm ²	sawn on foil

Mechanical Parameters

Meenamear r aramet				
Die size		7.5 x 7.5		
Area total		56.25	mm²	
Anode pad size		6.78 x 6.78		
Thickness		120	μm	
Wafer size		150	mm	
Max. possible chips pe	er wafer	248		
Passivation frontside		Photoimide		
Pad metal		3200 nm AlSiCu		
Backside metal		Ni Ag –system		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		Al, ≤500µm		
Reject ink dot size		Ø 0.65mm; max 1.2mm		
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 25 < 6 month		
	for open MBB bags	Acc. to IEC62258-3: Atmosphere >99% Nitrogen or ine Humidity <25%RH, Temperature 17°C – 25°C, < 6 n		



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Maximum Ratings

Parameter	Symbol	Condition	Value	Unit
Repetitive peak reverse voltage	V _{RRM}	<i>T</i> _{vj} = 25 °C	1200	V
Continuous forward current	I _F	<i>T</i> _{vj} < 150°C	1)	_
Maximum repetitive forward current ²⁾	I _{FRM}	<i>T</i> _{vj} < 150°C	150	A
Operating junction and storage temperature	$T_{\rm vj,} T_{\rm stg}$		-55+150	°C

¹⁾ depending on thermal properties of assembly

²) not subject to production test - verified by design/characterisation

Static Characteristics (tested on wafer), T_{vi} = 25 °C

Parameter	Symbol C	Conditions	Value			Unit
Falameter		Conditions	min.	typ.	max.	Unit
Reverse leakage current	I _R	V _R =1200V			20	μA
Cathode-Anode breakdown Voltage	V _{BR}	I _R =0.25mA	1200			V
Forward voltage drop	V _F	I _F =75A	1.68	2.1	2.42	

Electrical Characteristics (not subject to production test - verified by design/characterization)

Parameter		Symbol	Conditions	Value			Unit
Falametei		Symbol Conditions min.		typ.	max.	Onic	
Forward voltage drop	<i>T</i> _{vj} = 125°C	V _F	I _F =75A		1.7		V

Further Electrical Characteristics

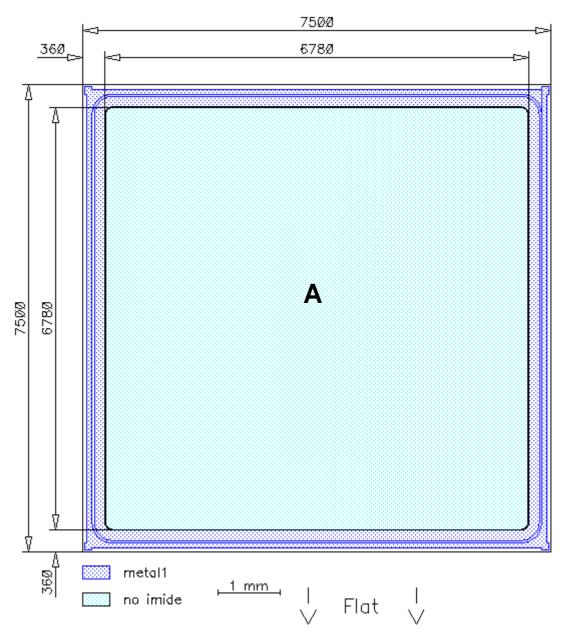
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

This chip data sheet refers to the device data sheet	F4-75R12KS4_B11	Rev. 2.0
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Chip Drawing



Die-Size 7500 um x 7500 um

A: Anode pad

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Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date

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